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AMENDMENTS TO THE SPECIFICATION**In the Specification:**

Please replace the two paragraphs beginning at page 12, line 3 with the following amended paragraphs:

Figure 2 is an illustration of a block diagram of a reticle defect inspection and/or correction system in accordance with an aspect of the invention. The inspection system 200 comprises an SEM 210, an FIB 220, and an ESCA 230, operatively coupled to permit inspection, analysis, and correction of reticle defects without requiring a defect identification or navigation system. In one example, the ESCA 230 can be replaced or supplemented by a FTIR 240. According to an aspect of the present invention, a processor 250 operatively coupled to the defect inspection system 200 directs the system 200 to scan the sample reticle. The processor 250 is operatively coupled to a memory 260. It is to be understood that a that the processor 250 can be a processor dedicated to determining whether defects and and/or or contaminants exist, a processor used to control one or more of the components of the inspection and/or correction system, or, alternatively, a processor that is both used to determine whether defects and/or contaminants exist and to control one or more of the components of the inspection and/or correction system. The memory 260 can be either volatile memory or nonvolatile memory, or can include both volatile and nonvolatile memory. By way of illustration, and not limitation, nonvolatile memory can include read only memory (ROM), programmable ROM (PROM), electrically programmable ROM (EPROM), electrically erasable ROM (EEPROM), or flash memory. Volatile memory can include random access memory (RAM), which acts as external cache memory. By way of illustration and not limitation, RAM is available in many forms such as synchronous RAM (SRAM), dynamic RAM (DRAM), synchronous DRAM (SDRAM), double data rate SDRAM (DDR SDRAM), enhanced SDRAM (ESDRAM), Synchlink DRAM (SLDRAM), and direct Rambus RAM (DRRAM). The memory 260 of the present systems and methods is intended to comprise, without being limited to, these and any other suitable types of memory.

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According to one example, the memory 260 can store information related to schedules for maintenance and/or replacement on reticles. For instance, if a sulfur signature is detected on a reticle, but no adder defect growth is evident, the invention can proceed with APC based on stored information tables ~~the~~ that can be predictive of a most appropriate time for reticle maintenance and/or removal. Such information can be based on, for example, average life-expectance of a reticle, number of exposure pulses, *etc.*